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An American National Standard

# Standard Test Method for Determination of the Spectral Mismatch Parameter Between a Photovoltaic Device and a Photovoltaic Reference Cell <sup>1</sup>

This standard is issued under the fixed designation E973; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ε) indicates an editorial change since the last revision or reapproval.

#### 1. Scope

- 1.1 This test method provides a procedure for the determination of a spectral mismatch parameter used in performance testing of photovoltaic devices.
- 1.2 The spectral mismatch parameter is a measure of the error introduced in the testing of a photovoltaic device that is caused by the photovoltaic device under test and the photovoltaic reference cell having non-identical quantum efficiencies, as well as mismatch between the test light source and the reference spectral irradiance distribution to which the photovoltaic reference cell was calibrated.
- 1.2.1 Examples of reference spectral irradiance distributions are Tables E490 or G173.
- 1.3 The spectral mismatch parameter can be used to correct photovoltaic performance data for spectral mismatch error.
- 1.4 Temperature-dependent quantum efficiencies are used to quantify the effects of temperature differences between test conditions and reporting conditions.
- 1.5 This test method is intended for use with linear photovoltaic devices in which short-circuit is directly proportional to incident irradiance.
- 1.6 The values stated in SI units are to be regarded as standard. No other units of measurement are included in this standard.
- 1.7 This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety, health, and environmental practices and determine the applicability of regulatory limitations prior to use.
- 1.8 This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recom-

mendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.

#### 2. Referenced Documents

2.1 ASTM Standards:<sup>2</sup>

E490 Standard Solar Constant and Zero Air Mass Solar Spectral Irradiance Tables

E772 Terminology of Solar Energy Conversion

E948 Test Method for Electrical Performance of Photovoltaic Cells Using Reference Cells Under Simulated Sunlight

E1021 Test Method for Spectral Responsivity Measurements of Photovoltaic Devices

E1036 Test Methods for Electrical Performance of Nonconcentrator Terrestrial Photovoltaic Modules and Arrays Using Reference Cells

E1125 Test Method for Calibration of Primary Non-Concentrator Terrestrial Photovoltaic Reference Cells Using a Tabular Spectrum

E1362 Test Methods for Calibration of Non-Concentrator Photovoltaic Non-Primary Reference Cells

G138 Test Method for Calibration of a Spectroradiometer
Using a Standard Source of Irradiance

G173 Tables for Reference Solar Spectral Irradiances: Direct Normal and Hemispherical on 37° Tilted Surface

SI10 Standard for Use of the International System of Units (SI): The Modern Metric System

## 3. Terminology

- 3.1 *Definitions*—Definitions of terms used in this test method may be found in Terminology E772.
  - 3.2 Definitions of Terms Specific to This Standard:
- 3.2.1 *test light source*, *n*—a source of illumination whose spectral irradiance will be used for the spectral mismatch calculation. The light source may be natural sunlight or a solar simulator.
- 3.3 *Symbols:* The following symbols and units are used in this test method:

<sup>&</sup>lt;sup>1</sup> This test method is under the jurisdiction of ASTM Committee E44 on Solar, Geothermal and Other Alternative Energy Sources and is the direct responsibility of Subcommittee E44.09 on Photovoltaic Electric Power Conversion.

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<sup>&</sup>lt;sup>2</sup> For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

- 3.3.1  $\lambda$ —wavelength (µm or nm).
- 3.3.2 D—as a subscript, refers to the device to be tested.
- 3.3.3 *R*—as a subscript, refers to the reference cell.
- 3.3.4 S—as a subscript, refers to the test light source.
- 3.3.5 *0*—as a subscript, refers to the reference spectral irradiance distribution.
  - 3.3.6 A—active area, (m<sup>2</sup>).
  - 3.3.7 *E*—irradiance (W·m<sup>-2</sup>).
- 3.3.8  $E_S(\lambda)$ —spectral irradiance, test light source  $(W \cdot m^{-2} \cdot \mu m^{-1})$  or  $W \cdot m^{-2} \cdot nm^{-1}$ .
- 3.3.9  $E_0(\lambda)$ —spectral irradiance, to which the reference cell is calibrated (W·m<sup>-2</sup>· $\mu$ m<sup>-1</sup> or W·m<sup>-2</sup>·nm<sup>-1</sup>).
- 3.3.9.1 *Discussion*—Following normal SI rules for compound units (see Practice SI10), the units for spectral irradiance, the derivative of irradiance, with respect to wavelength,  $dE/d\lambda$ , would be  $W \cdot m^{-3}$ . However, to avoid possible confusion with a volumetric power density unit and for convenience in numerical calculations, it is common practice to separate the wavelength in the compound unit. This compound unit is also used in Tables G173.
  - 3.3.10 *I*—short-circuit current (A).
  - 3.3.11  $J_L$ —light-generated photocurrent density (A·m<sup>-2</sup>).
  - 3.3.12 *M*—spectral mismatch parameter (dimensionless).
- 3.3.13  $Q(\lambda, T)$ —quantum efficiency (electrons per photon or %).
- 3.3.14  $\Theta(\lambda)$ —partial derivative of quantum efficiency with respect to temperature (electrons per photon·°C<sup>-1</sup> or %·°C<sup>-1</sup>).
  - 3.3.15  $R(\lambda)$ —spectral responsivity (A·W<sup>-1</sup>).
  - 3.3.16 T—temperature (°C).
- 3.3.17  $T_{R0}$ —temperature, at which the reference cell is calibrated (°C).
- 3.3.18  $T_{D0}$ —temperature, to which the short-circuit current of the device to be tested will be reported (°C).
- 3.3.18.1 *Discussion*—When reporting photovoltaic performance to Standard Reporting Conditions (SRC), it is common for  $T_{R0} = T_{D0} = 25$ °C.
  - 3.3.19 q—electron charge (C).
  - 3.3.20 h—Planck constant (J·s).
  - 3.3.21 *c*—speed of light (m·s<sup>-1</sup>).
  - 3.3.22  $\Delta T$ —temperature difference (°C).
- 3.3.23  $\varepsilon$ —measurement error in short-circuit current (dimensionless).

# 4. Summary of Test Method

- 4.1 Spectral mismatch error occurs when a calibrated reference cell is used to measure total irradiance of a test light source (such as a solar simulator) during a photovoltaic device performance measurement, and the incident spectral irradiance of the test light source differs from the reference spectral irradiance distribution to which the reference cell is calibrated.
- 4.2 The magnitude of the error depends on how the quantum efficiencies of the photovoltaic reference cell and the device to

be tested differ from one another; these quantum efficiencies vary with temperature.

- 4.3 Determination of the spectral mismatch parameter *M* requires six spectral quantities.
- 4.3.1 The spectral irradiance distribution of the test light source  $E_s(\lambda)$ .
- 4.3.2 The reference spectral irradiance distribution to which the photovoltaic reference cell was calibrated  $E_0(\lambda)$ .
  - 4.3.3 Photovolatic Reference Cell:
- 4.3.3.1 The quantum efficiency at the temperature corresponding to its calibration constant,  $Q_R(\lambda T_0)$
- 4.3.3.2 The partial derivative of the quantum efficiency with respect to temperature,  $\Theta_R(\lambda) = \partial Q_R / \partial T(\lambda)$ .
  - 4.3.4 Device to be Tested:
- 4.3.4.1 The quantum efficiency at the temperature at which its performance will be reported,  $Q_D(\lambda, T_{D0})$ .
- 4.3.4.2 The derivative of the quantum efficiency with respect to temperature,  $\Theta_R(\lambda) = \partial Q_D / \partial T(\lambda)$
- 4.4 Temperatures of both devices are measured, and M is calculated using Eq 1 and numerical integration.

#### 5. Significance and Use

- 5.1 The calculated error in the photovoltaic device current determined from the spectral mismatch parameter can be used to determine if a measurement will be within specified limits before the actual measurement is performed.
- 5.2 The spectral mismatch parameter also provides a means of correcting the error in the measured device current due to spectral mismatch.
- 5.2.1 The spectral mismatch parameter is formulated as the fractional error in the short-circuit current due to spectral and temperature differences.
- 5.2.2 Error due to spectral mismatch is corrected by multiplying a reference cell's measured short-circuit current by M, a technique used in Test Methods E948 and E1036.
- 5.3 Because all spectral quantities appear in both the numerator and the denominator in the calculation of the spectral mismatch parameter (see 8.1), multiplicative calibration errors cancel, and therefore only relative quantities are needed (although absolute spectral quantities may be used if available).
- 5.4 Temperature-dependent spectral mismatch is a more accurate method to correct photovoltaic current measurements compared with fixed-value temperature coefficients.<sup>3</sup>

#### 6. Apparatus

- 6.1 Quantum Efficiency Measurement Apparatus—As required by Test Method E1021 for spectral responsivity measurements.
- 6.2 Spectral Irradiance Measurement Equipment—A spectroradiometer as defined and required by Test Method G138 and calibrated according to Test Method G138.

<sup>&</sup>lt;sup>3</sup> Osterwald, C. R., Campanelli, M., Moriarty, T., Emery, K. A., and Williams, R., "Temperature-Dependent Spectral Mismatch Corrections," *IEEE Journal of Photovoltaics*, Vol 5, No. 6, November 2015, pp. 1692–1697. DOI:10.1109/JPHOTOV.2015.2459914

- 6.2.1 The wavelength resolution shall be no greater than 10 nm.
- 6.2.2 It is recommended that the wavelength pass-bandwith be no greater than 6 nm.
- 6.2.3 The wavelength range should be wide enough to include the quantum efficiencies of both the photovoltaic device to be tested and the photovoltaic reference cell.
- 6.2.4 The spectroradiometer must be able to scan the required wavelength range in a time period short enough such that the spectral irradiance at any wavelength does not vary more than  $\pm 5$  % during the entire scan.
- 6.2.5 Test Methods E948, E1036, and E1125 provide additional guidance for spectral irradiance measurements.
- 6.3 *Temperature Measurement Equipment*—As required by Test Method E948 or Test Methods E1036.

#### 7. Procedure

- 7.1 Obtain the reference spectral irradiance distribution,  $E_0(\lambda)$ , to which the photovoltaic reference cell is calibrated, such as Tables E490 or G173.
- 7.2 Obtain the quantum efficiency of the photovoltaic reference cell at its calibration temperature,  $Q_R(\lambda, T_{R0})$ .
- 7.2.1 An expression that converts spectral responsivity to quantum efficiency is provided in Test Methods E1021.

Note 1—Test Methods E1125 and E1362 require the spectral responsivity to be provided as part of the reference cell calibration certificate.

- 7.3 Obtain the partial derivative of quantum efficiency with respect to temperature,  $\Theta_R(\lambda)$ , for the photovoltaic reference cell (see 8.1).
- 7.3.1 If  $\Theta_R(\lambda)$  is not provided with the calibration certificate of the photovoltaic reference cell, the derivatiave function must be calculated from a series of quantum efficiency measurements at several temperatures. An acceptable procedure is given in Annex A1.
- 7.4 Measure the quantum efficiency of the photovoltaic device to be tested at the temperature to which its performance will be reported,  $Q_D(\lambda, T_{D0})$ , and its partial derivative of quantum efficiency with respect to temperature,  $\Theta_D(\lambda)$ , using the procedure given in Annex A1(see also 8.1).
- 7.5 Measure the spectral irradiance,  $E_S(\lambda)$ , of the test light source, using the spectral irradiance measurement equipment (see 6.2.1).
- 7.6 Measure the temperature of the photovoltaic reference cell,  $T_R$ , using the temperature measurement equipment.
- 7.7 Measure the temperature of the photovoltaic device to be tested,  $T_D$ , using the temperature measurement equipment.

# 8. Calculation of Results

8.1 Calculate the spectral mismatch parameter with:<sup>3</sup>

$$M = \frac{\int_{\lambda_1}^{\lambda_2} \lambda Q_D(\lambda, T_{D0}) E_S(\lambda) d\lambda + \Delta T_D \int_{\lambda_1}^{\lambda_2} \lambda \Theta_D(\lambda) E_S(\lambda) d\lambda}{\int_{\lambda_3}^{\lambda_4} \lambda Q_R(\lambda, T_{R0}) E_S(\lambda) d\lambda + \Delta T_R \int_{\lambda_3}^{\lambda_4} \lambda \Theta_R(\lambda) E_S(\lambda) d\lambda}$$

$$\times \frac{\int_{\lambda_3}^{\lambda_4} \lambda Q_R(\lambda, T_{R0}) E_0(\lambda) d\lambda}{\int_{\lambda_1}^{\lambda_2} \lambda Q_D(\lambda, T_{D0}) E_0(\lambda) d\lambda},$$
(1)

where  $\Delta T_R = T_R - T_{R0}$  and  $\Delta T_D = T_D - T_{D0}$ . Use an appropriate numerical integration scheme such as that described in Tables G173. Appendix X1 provides the derivation of Eq 1. If  $|\Delta T_R| \leq 0.5^{\circ}\mathrm{C}$  and  $|\Delta T_D| \leq 0.5^{\circ}\mathrm{C}$ , then  $\Theta_R(\lambda)$  and  $\Theta_D(\lambda)$  may be omitted and Eq 1 simplified to:

$$M = \frac{\int_{\lambda_1}^{\lambda_2} \lambda Q_D(\lambda, T_{D0}) E_S(\lambda) d\lambda}{\int_{\lambda_3}^{\lambda_4} \lambda Q_R(\lambda, T_{R0}) E_S(\lambda) d\lambda} \times \frac{\int_{\lambda_3}^{\lambda_4} \lambda Q_R(\lambda, T_{R0}) E_0(\lambda) d\lambda}{\int_{\lambda_1}^{\lambda_2} \lambda Q_D(\lambda, T_{D0}) E_0(\lambda) d\lambda}, \quad (2)$$

- 8.1.1 The wavelength integration limits  $\lambda 1$  and  $\lambda 2$  shall correspond to the spectral response limits of the photovoltaic device.
- 8.1.2 The wavelength integration limits  $\lambda 3$  and  $\lambda 4$  shall correspond to the spectral response limits of the photovoltaic reference cell.
- 8.2 *Optional*—Calculate the measurement error due to spectral mismatch using:

$$\varepsilon = |M - 1| \tag{3}$$

### 9. Precision and Bias

- 9.1 *Precision*—Imprecision in the spectral irradiance and the spectral response measurements will introduce errors in the calculated spectral mismatch parameter.
- 9.1.1 It is not practicable to specify the precision of the spectral mismatch test method using results of an interlaboratory study, because such a study would require circulating at least six stable test light sources between all participating laboratories.
- 9.1.2 Monte-Carlo perturbation simulations<sup>4</sup> using precision errors as large as 5 % in the spectral measurements have shown that the imprecision associated with the calculated spectral mismatch parameter is no more than 1 %.
- 9.1.3 Table 1 lists estimated maximum limits of imprecision that may be associated with spectral measurements at any one wavelength.
- 9.2 *Bias*—Bias associated with the spectral measurements used in the spectral mismatch calculation can be either independent of wavelength or can vary with wavelength.
- 9.2.1 Numerical calculations using wavelength-independent bias errors of 2 % added to the spectral quantities show the error introduced in the spectral mismatch parameter to be less than 1 %.
- 9.2.2 Estimates of maximum bias that may be associated with the spectral measurements are listed in Table 2. These limits are listed for guidance only and in actual practice will depend on the calibration of the spectral measurements.

TABLE 1 Estimated Limits of Imprecision in Spectral Measurements

Source of Imprecision	Estimated Limit, %
Spectral response measurement	2.0
Spectral irradiance measurement	5.0

<sup>&</sup>lt;sup>4</sup> Emery, K. A., Osterwald, C. R., and Wells, C. V., "Uncertainty Analysis of Photovoltaic Efficiency Measurements," *Proceedings of the 19th IEEE Photovoltaics Specialists Conference—1987*, pp. 153–159, Institute of Electrical and Electronics Engineers, New York, NY, 1987.